

Laboratory	SAC (ISRO)-TIMCD-Calibration Laboratory, Space Applications Centre, Department of Space, Government of India, Ambawadi Vistar Post Office, Jodhpur Tekra, Ahmedabad, Gujarat		
Accreditation Standard	ISO/IEC 17025: 2005		
Discipline	Electro-Technical Calibration	Issue Date	20.10.2014
Certificate Number	C-0556	Valid Until	19.10.2016
Last Amended on	-	Page	1 of 7

Quantity Measured/ Instrument	Range / Frequency	*Calibration Measurement Capability (\pm)	Remarks
<u>SOURCE</u>			
1. DC VOLTAGE^{\$}	10 V	4.0 μ V	Using DC Reference Standard Fluke /734A(732B) By Direct Method
	100 mV to 1V 1 V to 10V 10V to 100V 100 V to 1000 V	0.66 μ V to 4 μ V 4 μ V to 35 μ V 35 μ V to 0.5 mV 0.5 mV to 5 mV	Using Calibrator Fluke/5720A By Direct Method
2. AC VOLTAGE^{\$}	100 Hz to 1 kHz 100 mV to 1 V 1 V to 10 V 10 V to 100 V 100 V to 1000 V	10 μ V to 50 μ V 50 μ V to 0.50mV 0.50 mV to 10 mV 10 mV to 0.16 V	Using Calibrator Fluke/5720A By Direct Method
	1 kHz to 20 kHz 500 V to 1000 V	10 mV to 0.16 V	Using Calibrator Fluke/5720A with Fluke / 5725A Amplifier By Direct Method
	1 kHz to 100 kHz 100 mV to 1V 1 V to 10 V 10 V to 100 V 100 V to 500 V	12 μ V to 0.13 mV 0.13 mV to 1.2 mV 1.2 mV to 12 mV 12 mV to 0.19 V	Using Calibrator Fluke/5720A with Fluke / 5725A Amplifier By Direct Method
	100 kHz to 300 kHz 1 V to 10 V	0.13 mV to 5 mV	Using Calibrator Fluke/5720A By Direct Method

Shally Sharma
Convenor

Avijit Das
Program Manager

Laboratory	SAC (ISRO)-TIMCD-Calibration Laboratory, Space Applications Centre, Department of Space, Government of India, Ambawadi Vistar Post Office, Jodhpur Tekra, Ahmedabad, Gujarat		
Accreditation Standard	ISO/IEC 17025: 2005		
Discipline	Electro-Technical Calibration	Issue Date	20.10.2014
Certificate Number	C-0556	Valid Until	19.10.2016
Last Amended on	-	Page	2 of 7

Quantity Measured/ Instrument	Range / Frequency	*Calibration Measurement Capability (\pm)	Remarks
3. DC CURRENT ^{\$}	100 μ A to 1 mA 1 mA to 1 A 1 A to 10 A	5 nA to 30 nA 30 nA to 50 μ A 50 μ A to 0.8 mA	Using Calibrator Fluke/5720A with Fluke / 5725A Amplifier By Direct Method
4. AC CURRENT ^{\$}	100 Hz to 1kHz 100 μ A to 1 mA 1 mA to 100 mA 100 mA to 1 A 1 A to 10 A 1 kHz to 10 kHz 1 mA to 100 mA 100 mA to 10 A	31 nA to 0.15 μ A 0.15 μ A to 15 μ A 15 μ A to 0.2 mA 0.2 mA to 3 mA 0.60 μ A to 60 μ A 60 μ A to 4 mA	Using Calibrator Fluke/5720A with Fluke/ 5725A Amplifier By Direct Method
5. DC RESISTANCE ^{\$}	1 Ω 10 k Ω 1 G Ω 1 Ω & 1.9 Ω 10 Ω & 19 Ω 100 Ω & 190 Ω 1k Ω & 1.9 k Ω 10 k Ω & 19 k Ω 100 k Ω & 190 k Ω 1 M Ω & 1.9 M Ω 10 M Ω & 19 M Ω 100 M Ω	3 $\mu\Omega$ 23.7 m Ω 0.37 M Ω 50 $\mu\Omega$ & 60 $\mu\Omega$ 70 $\mu\Omega$ & 0.1 m Ω 0.5 m Ω & 0.6 m Ω 5 m Ω & 6 m Ω 50 m Ω & 60 m Ω 0.3 Ω & 0.5 Ω 10 Ω & 15 Ω 0.22 k Ω & 0.5 k Ω 16 k Ω	Using Tinsley/5685A, Standard By Direct Method Using Resistor Guildline /9330, Standard. By Direct Method Using Resistor Fluke/ 8508A- 7000K Standard Resistor By Direct Method Using Calibrator Fluke/5720A By Direct Method

Shally Sharma
Convenor

Avijit Das
Program Manager

Laboratory	SAC (ISRO)-TIMCD-Calibration Laboratory, Space Applications Centre, Department of Space, Government of India, Ambawadi Vistar Post Office, Jodhpur Tekra, Ahmedabad, Gujarat		
Accreditation Standard	ISO/IEC 17025: 2005		
Discipline	Electro-Technical Calibration	Issue Date	20.10.2014
Certificate Number	C-0556	Valid Until	19.10.2016
Last Amended on	-	Page	3 of 7

Quantity Measured/ Instrument	Range / Frequency	*Calibration Measurement Capability (\pm)	Remarks
6. FREQUENCY^s	10 MHz	5×10^{-12}	Using Cesium Beam Frequency Standard, Oscilloquartz/5585 By Direct Method
	1-2-2.5-5- 10 MHz	2×10^{-12}	Using Frequency Difference Multiplier Adert / 4110A By Direct Method
	50 Hz to 1MHz 1 MHz to 10MHz	0.01 mHz to 2mHz 2 mHz to 20 mHz	Using AWG Wavetek/39 By Direct Method
	10 MHz to 1 GHz 1 GHz to 40 GHz	0.6 Hz to 1.5 Hz 1.5 Hz to 23 Hz	Using 5PSG CW Signal Gen, Agilent / E8247C By Direct Method
7. RF POWER^s	10 MHz to 40GHz 1 pW to 20 mW (-90 dBm to +13 dBm)	7 % to 10 %	Using PSG CW Signal Gen; Agilent/ E8247C By Direct Method
8. CAL FACTOR^s (CF)	10 MHz to 26.5 GHz @ 1 mW 0.85 to 1	4%	Using Sensor Cal System Tegam/1806A, F1135A & DMM Keithley 2000 By Direct Method
	26.5 GHz to 40 GHz @ 1 mW 0.85 to 1	5%	Using Sensor Cal System Tegam/1806A, 1107-08 & DMM Keithley 2000 By Direct Method

Shally Sharma
Convenor

Avijit Das
Program Manager

Laboratory	SAC (ISRO)-TIMCD-Calibration Laboratory, Space Applications Centre, Department of Space, Government of India, Ambawadi Vistar Post Office, Jodhpur Tekra, Ahmedabad, Gujarat		
Accreditation Standard	ISO/IEC 17025: 2005		
Discipline	Electro-Technical Calibration	Issue Date	20.10.2014
Certificate Number	C-0556	Valid Until	19.10.2016
Last Amended on	-	Page	4 of 7

Quantity Measured/ Instrument	Range / Frequency	*Calibration Measurement Capability (\pm)	Remarks
9. OSCILLOSCOPE^s			
1) Voltage (Amplitude)			
a. DC Signal (1MΩ)	2 mV to 220 V	2 μ V to 0.12 mV	Using Oscilloscope Calibrator / Wavetek (Fluke) / 9500B with 9530/9560 Active Head By Direct Comparison Substitution Method
b. DC Signal (50Ω)	2 mV to 5 V	2 μ V to 1.2 mV	
c. Square Wave (1MΩ)	2 mV to 220 Vp-p	10 μ V to 75 mVp-p	
d. Square Wave (50Ω)	2 mV to 5 Vp-p	10 μ V to 1.5 mVp-p	
2) Time Base	3.3 ns to 10 ms	60 fs to 0.8 μ s	
3) Bandwidth	3.2 GHz	3.2 %	
	6.4 GHz	5 %	
1. <u>MEASURE</u> DC VOLTAGE^s	100 mV to 1V 1 V to 10 V 10 V to 100V 100 V to 1000 V	0.6 μ V to 4 μ V 4 μ V to 35 μ V 35 μ V to 0.5 mV 0.5 mV to 5 mV	Using 8 ½ Multimeter Fluke/8508A By Direct Method
2. AC VOLTAGE^s	100 Hz to 20 kHz 100 mV to 1 V 1 V to 10 V 10 V to 100 V 100 V to 1000 V	10 μ V to 50 μ V 50 μ V to 0.4 mV 0.4 mV to 10 mV 10 mV to 0.15 V	Using 8 ½ Multimeter Fluke/8508A By Direct Method
	20 kHz to 100 kHz 100 mV to 1 V 1 V to 10 V 10 V to 100 V 1 V	10 μ V to 0.12mV 0.12mV to 1.1mV 1.1 mV to 12 mV 1.1 mV	
3. DC CURRENT^s	100 μ A to 1mA 1 mA to 1 A 1 A to 10 A	2 nA to 20 nA 20 nA to 40 μ A 40 μ A to 1 mA	Using 8 ½ Multimeter Fluke/8508A By Direct Method

Shally Sharma
Convenor

Avijit Das
Program Manager

Laboratory	SAC (ISRO)-TIMCD-Calibration Laboratory, Space Applications Centre, Department of Space, Government of India, Ambawadi Vistar Post Office, Jodhpur Tekra, Ahmedabad, Gujarat		
Accreditation Standard	ISO/IEC 17025: 2005		
Discipline	Electro-Technical Calibration	Issue Date	20.10.2014
Certificate Number	C-0556	Valid Until	19.10.2016
Last Amended on	-	Page	5 of 7

Quantity Measured/ Instrument	Range / Frequency	*Calibration Measurement Capability (\pm)	Remarks
4. AC CURRENT^{\$}	100 Hz to 1 kHz 100 μ A to 1 mA 1 mA to 100 mA 100 mA to 1 A 1 A to 10 A	20 nA to 0.15 μ A 0.15 μ A to 10 μ A 10 μ A to 0.15 mA 0.15 mA to 2 mA	Using 8 ½ Multimeter Fluke/8508A By Direct Method
	1 kHz to 10 kHz 10 mA to 1 A 1 A to 10 A	1 μ A to 0.2 mA 0.2 mA to 2 mA	
5. DC RESISTANCE^{\$}	1 Ω to 100 Ω	8 Ω to 0.5 m Ω	Using 8 ½ Multimeter Fluke/8508A By Direct Method
	100 V to 10 k Ω	0.5 m Ω to 50 m Ω	
	10 k Ω to 1 M Ω	50 m Ω to 10 Ω	
	1 M Ω to 10 M Ω	10 Ω to 200 Ω	
	10 M Ω to 100 M Ω 100 M Ω to 1 G Ω	0.2 k Ω to 15 k Ω 15 k Ω to 0.3 M Ω	
6. FREQUENCY^{\$}	1 Hz to 300 MHz	0.1 mHz to 1.5 Hz	Using Timer/Counter Pendulum CNT-90 By Direct Method
	10 Hz to 40 GHz	0.6 Hz to 25 Hz	Using Frequency Counter Agilent/53152A By Direct Method
7. RF POWER^{\$}	10 MHz to 26.5 GHz 10 μ W to 25 mW (-20 dBm to +14 dBm)	4 %	Using Sensor Cal System Tegam 1806A & M1135A By Direct Method

Shally Sharma
Convenor

Avijit Das
Program Manager

Laboratory	SAC (ISRO)-TIMCD-Calibration Laboratory, Space Applications Centre, Department of Space, Government of India, Ambawadi Vistar Post Office, Jodhpur Tekra, Ahmedabad, Gujarat		
Accreditation Standard	ISO/IEC 17025: 2005		
Discipline	Electro-Technical Calibration	Issue Date	20.10.2014
Certificate Number	C-0556	Valid Until	19.10.2016
Last Amended on	-	Page	6 of 7

Quantity Measured/ Instrument	Range / Frequency	*Calibration Measurement Capability (\pm)	Remarks
	10 MHz to 40 GHz 1 nW to 100 mW (-60 dBm to +20 dBm)	5 % to 8 %	Using RF Power meter Agilent N1914A with N8487A/ 8487D / N8485A By Direct Method
	10 MHz to 40 GHz 100 pW to 10 nW (-70 dBm to -50 dBm)	6 % to 9 %	Using Spectrum analyzer R&S FSU67/ Agilent E4446A By Direct Method
	10 MHz to 40 GHz 1 pW to 100 pW (-90 dBm to -70 dBm)	7 % to 12 %	
8. AMPLITUDE MODULATION^{\$} (AM)	Mod.Depth: 5 % to 99% (Fc: 100 kHz to 2 GHz Fm: 100 Hz to 10 kHz)	0.5 % to 2 %	Using Modulation Analyzer Boonton / 8201
9. FREQUENCY MODULATION^{\$} (FM)	Deviation: 10 kHz to 199 kHz (Fc: 100 kHz to 2 GHz Fm: 100 Hz to 10 kHz)	0.20 kHz to 4 kHz	Using Modulation Analyzer Boonton / 8201 By Direct Method
10. REFLECTION CO-EFFICIENT^{\$}	Frequency: 10 MHz to 40 GHz 0.002 to 0.33	0.04 to 0.11	Using Vector Network Analyzer, Anritsu / MS4644A By Direct Method

Shally Sharma
Convenor

Avijit Das
Program Manager

Laboratory SAC (ISRO)-TIMCD-Calibration Laboratory, Space Applications Centre,
Department of Space, Government of India, Ambawadi Vistar Post
Office, Jodhpur Tekra, Ahmedabad, Gujarat

Accreditation Standard ISO/IEC 17025: 2005

Discipline Electro-Technical Calibration **Issue Date** 20.10.2014

Certificate Number C-0556 **Valid Until** 19.10.2016

Last Amended on - **Page** 7 of 7

Quantity Measured/ Instrument	Range / Frequency	*Calibration Measurement Capability (\pm)	Remarks
11. ATTENUATION ^{\$}	Frequency: 10MHz to 40GHz 0 dB to 50 dB (Lin: 1 to 0.00316)	1.6 % to 6 %	Using Vector Network Analyzer, Anritsu / MS4644A By Direct Method

* Measurement Capability is expressed as an uncertainty (\pm) at a confidence probability of 95%

^{\$}Only in Permanent Laboratory

Shally Sharma
Convenor

Avijit Das
Program Manager